Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/768,627	LEE ET AL.	EE ET AL.
Examiner	Art Unit	rt Unit
Steve R. Crow	3764	764

SEARCHED						
Class	Subclass	Date	Examiner			
	51					
482	52					
	57					
	70					
	79-80	1-3-05	DRC			

INTERFERENCE SEARCHED					
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482	51-52				
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